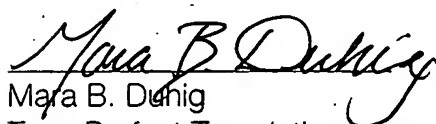# TRANSPERFECT
TRANSLATIONS

AFFIDAVIT OF ACCURACY

I, Mara B. Duhig, hereby certify that the following document is, to the best of my knowledge and belief, a true and accurate translation from German into English.

Mara B. Duhig
TransPerfect Translations, Inc.
601 Thirteenth Street, NW
Suite 320 North
Washington, DC 20005

Sworn to before me this
14th day of July 2005

Signature, Notary Public

Lisa Sherfinski
Notary Public, District of Columbia
My Commission Expires 01-01-2008

Stamp, Notary Public

District of Columbia

Windmöller & Hölscher KG

Münsterstrasse 50

49525 Lengerich/Westfalen

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Process For The Automatic Control Of The Thickness Of Extruded Film

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The present invention relates to a process for the automatic control of the thickness of extruded film.

15 Processes of such type are used both in flat sheet film extrusion as well as in blown film extrusion.

In modern extrusion plants, these processes usually comprise the following process steps, which are also specified in the preamble of the main claim 1:

- Measurement of the thickness profile of the film just extruded with the help of
20   a thickness-measuring probe that is moved along the surface of the film substantially perpendicular (x) to the conveying direction (z) of the extruded film. The thickness-measuring probe records for each measuring cycle (MZ) a thickness profile (P) of the film at least across parts of the expansion of the film perpendicular (x) to its conveying direction (z),

25 - Transmitting the measured values to a control unit,

- Storage of the measured values underlying the thickness profiles in a storage unit,

- Provision of statistical values of the film thickness (5) using a computer (14), whereby the computer (14) takes into account measured values or information
30   derived therefrom using a definite number (N) of measuring cycles (MZ) and, if necessary, provides measured values from recent and older measuring cycles with different weighting factors,

- Determination of the deviations in the statistical values of the film thickness from a target value,

- Generating control commands to a device for controlling the film thickness.

5   The measuring devices outlined above are known from published prior art. Thus the patent specification DE 40 09 982 A1 proposes a capacitive sensor for measuring the thickness of the wall of a film tube. However, even other principles of measurement are used to measure the film thickness. For instance, even the measurements of the transmission behavior of beta radiation, gamma radiation, x-radiation and infrared

10   radiation have proved to be useful. In blown film plants they are usually guided around the film tube that is just extruded. In flat film plants the sensor traverses across the width of the flat film extruded.

     In this connection, statistical specifications about the development of the film

15   thickness in terms of time generated using a computer serve to avoid an overmodulation or overshooting of the control process. For this purpose the computer takes into account measured values of a definite number of measuring cycles. The statistical values usually involve the computation of an average value or meridian. However, it is also possible to determine other statistical parameters.

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     Furthermore, it is possible to provide the computer with information derived from the measured values instead of the measured values themselves. This information derived from the measured values can be statistical values that result in the updated statistical values by taking into account the most recent measured values. Thus, for instance, an

25   average value can be computed by feeding the average value of the last N measurements to the computer. The computer then only has to take into account the current measured value while computing the updated average value.

     Information derived from measured values can also exist in the form of recorded

30   "older" control commands that are adjusted on the basis of current measured values.

Measured values from a definite number of measuring cycles are used while computing the statistical values. Often measured values from a definite number of measuring cycles, for instance, the last N measuring cycles are used. Finally, in order to compute the average value the sum of the measured values at definite positions in

5   x-direction is calculated and divided by N.

Furthermore, various methods can be used to determine the contribution of the measured values from different measuring cycles in the computation of the statistical values. Thus, for instance, greater importance can be accorded to the more recent, just recorded measured values than to the older values while computing the statistical

10   values.

This variable weighting of the measured values, in short MW_n, can be carried out with the help of weighting factors, here k_n. In a statistical function that is similar to the average value computation, the sum would be computed as follows:

15

$$\Sigma = k_1 MW_1 + k_2 MW_2 + \ldots + k_n MW_n$$

However, in this example, this sum would not be divided only by N, instead by the sum

20   $$\Sigma = k_1 + k_2 + \ldots + k_n$$

in order to derive the statistical value similar to the average value. The information derived by the computer from the measured values and/or the statistical values is fed to a control unit that controls a device for controlling the film thickness. The thickness of the film can be controlled using different means. Thus, for instance, the width of

25   the die gap or of the die ring can be varied in certain sections in order to be able to increase or decrease the throughflow of the melt at the desired places.

However, the control unit can also control the temperature of the melt by means of heating or cooling agents. Using the temperature it is possible to control in a targeted manner the viscosity of the melt. Should the viscosity of a melt be higher in one place than in other places, then the melted mass can "melt" more strongly in this place, thus

5   causing the film to have a lesser thickness in this place.

Likewise the thickness of the film can be changed by stretching it in certain places. In this context, the property of the film that allows the already solidified and partially cooled film to stretch is exploited. The regions of the film that are stretched more

10   strongly subsequently exhibit a lesser thickness than the regions of the film that are stretched using lesser strength. The force required for stretching the film is frequently made available by blow air. In this case the control unit controls the volume flow of the blow air in certain regions.

15   The measurement processes described above have proved to be useful in practice particularly in continuous operation. However, since in recent times a trend toward job orders of smaller sizes and thus toward a more frequent change-over of the film material can been noted, increasingly greater significance is attached to the automatic control of the film thickness at the start of the extrusion process.

20

However, film materials with unacceptable thickness tolerances and thus rejections have been produced using automatic control processes according to prior art during an important time span at the start of the extrusion process.

25   Therefore the objective of the present invention is to lower more quickly the deviations in the thickness of the film after the start of the extrusion process.

This objective is achieved by the fact that

-     While providing the statistical values in relation to the older measured values,

30   the latest measured value(s) during a predetermined time-frame at the start of the extrusion process are more heavily weighted by the computer (14) than those measured during the normal operation.

By heavily weighting the more recent measured values, the thickness deviations at the start of the measuring process can be reduced. The stronger consideration of the more recently recorded measured values according to the invention is advantageously possible by lowering the number (N) of the measuring cycles from which the

5   measured values are taken into account and/or by changing the weighting factors (k_n) with respect to the usual values in the normal operation.

However, it appears inexpedient to retain the process of strong consideration of the more recent, just derived measured values during the entire operation because it makes the control process too sensitive to variations. Therefore, the statistical

10   parameters mentioned above (N and k_n) should be traced back in the course of the extrusion process to the values of the normal operation.

The required control of the number of measuring cycles from which the measured values are weighted and/or the change of the weighting factors to the usual values in the normal operation takes place advantageously in a series of steps within a large

15   number of measuring cycles.

The object of this patent application is also a device that is suitable for executing the process according to the invention.

20   An embodiment of the invention can be based on the drawings and the graphic representation.

The individual figures show:

Fig. 1   side view of a device according to the invention for manufacturing a

25   film using the process pursuant to the invention.

Fig. 2   top view of the device illustrated in fig. 1

Figures 1 and 2 illustrate a device for manufacturing extruded films. A granulate is used as the starting material for manufacturing the films. The granulate is fed to the

5   device by means of the feed hopper 1. From there the granulate enters into the extruder 2 in which it is molten by applying high pressure and heat. This melt is fed to the sheet die 4 using the pipeline 3. The melt is substantially distributed inside the sheet die 4 on its entire width. The melt emerges from the die gap 5 and arrives onto the chill roller 6. The gap width of the die gap 5 can be changed in certain sections in

10   a manner that is not illustrated here. The melt solidifies on the chill roller and becomes film 8. This film 8 wraps around the chill roller 6 to a large extent and is cooled down strongly by the latter. The film 8 is fed by means of a deflecting roller 7 to a winding device 9 where it is wound up into a roll 10.

15   A thickness-measuring device 11 measures the thickness of the film 8 after it has passed the deflecting roller 7. The thickness-measuring device 11 comprises of the thickness-measuring probe 12 that consists of a transmitter 12a and a receiver 12b. The measured values are fed by means of a data line 13 to the computer and storage unit 14. The machine operator can access the measured values or the information

20   derived therefrom by means of the monitor 15. The monitor 15 can also be used for the input of parameters. If necessary, another input device that is not illustrated here can also be used for this purpose. The computer and storage unit 14 provides information to the control unit 17 by means of the data line 16 for controlling the device that controls the thickness of the film. From this information the control unit

25   17 determines control commands and transmits these using the control line 18 to the device that controls the thickness of the film. In the embodiment of the present invention illustrated here the control commands are used for varying the gap width of the die gap 5.

Figure 2 illustrates the effective progression of the path 19 created by the measuring heads 12 if they move at a uniform speed in the direction (x) perpendicular to the conveying direction (z) of the film 8. For the purpose of determining a complete thickness profile of the film 8, the measuring heads 12 move up to the borders of the

5 film 8.

List of Reference Symbols	
1	Feed hopper
2	Extruder
3	Pipeline
4	Sheet die
5	Die gap
6	Chill roller
7	Deflecting roller
8	Film
9	Winding device
10	Roll
11	Thickness-measuring device
12	Thickness-measuring probe
13	Data line
14	Computer and storage unit
15	Monitor
16	Data line
17	Control unit
18	Control line
19	Effective path progression
12a	Transmitter of the thickness-measuring probe
12b	Receiver of the thickness-measuring probe
x	Direction of movement of the measuring head 11
z	Conveying direction